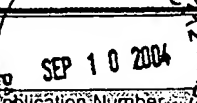



In place of PTO-1449 Form		U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number		10/816,730	
				Filing Date		April 2, 2004	
				Applicant(s)		Chun-Chieh Lin	
				Art Unit		2818	
				Examiner Name		To Be Determined	
SHEET 1 OF 1				Attorney Docket Number		24061.188 (TSMC2003-1374)	

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OTHER PRIOR ART				
Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item, date, page(s), volume, issue number(s), publisher, city/country where published		
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Examiner Signature		Date Considered	04/11/05
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.